

IEEE 1687 compliant ecosystem for embedded instrumentation access and in-field health monitoring

Tšertov, Anton; Jutman, Artur; Shibin, Konstantin; **Devadze, Sergei** IEEE AUTOTESTCON 2018 : National Harbor, September 17-20, 2018 : proceedings 2018 / 9 p.: ill <https://doi.org/10.1109/AUTEST.2018.8532559>

IEEE P1687 IJTAG demonstrator on FPGA

Shibin, Konstantin; **Aleksejev, Igor**; Jutman, Artur; **Devadze, Sergei** DATE 2012 University Booth : Design Automation and Test in Europe : Dresden, Germany, March 12-16, 2012 2012 / 1 p. : ill
https://www.academia.edu/22101517/IEEE_P1687_IJTAG_demonstrator_on_FPGA

Invited paper: System-Wide Fault Management based on IEEE P1687 IJTAG

Jutman, Artur; **Devadze, Sergei**; **Aleksejev, Jevgeni** 6th International Workshop on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC) : 20-22 June 2011, Montpeillier, France 2011 / [4] p.: ill <https://ieeexplore.ieee.org/document/5981520>

Optimization of boundary scan tests using FPGA-based efficient scan architectures

Aleksejev, Igor; **Devadze, Sergei**; Jutman, Artur; **Shibin, Konstantin** Journal of electronic testing : theory and applications (JETTA) 2016 / p. 245-255 : ill <https://doi.org/10.1007/s10836-016-5588-y> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Reliable health monitoring and fault management infrastructure based on embedded instrumentation and IEEE 1687

Jutman, Artur; **Shibin, Konstantin**; **Devadze, Sergei** IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 240-249 : ill <https://doi.org/10.1109/AUTEST.2016.7589605>

System-wide fault management based on IEEE P1687 IJTAG

Shibin, Konstantin; Jutman, Artur; **Devadze, Sergei** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kuuenda aastakonverentsi artiklite kogumik : 3.-5. oktoobril 2012, Laulasmaa 2012 / p. 81-84 : ill